

102nd ARFTG Microwave Measurement Symposium

Software Architectures and Automation of
Microwave Measurement Methods and Systems



Monday, January 22nd

♀ Republic ABC	
13:30 – 13:40	Welcome to the 102nd ARFTG Symposium Introduction Conference Co-Chairs: Andrej Rumiantsev, Joe Gering TPC Co-Chairs: Dennis Lewis and Jeffrey Jargon
♀ Republic ABC	
13:40 – 15:00	Session A: Advances in Measurements Session Chair: Jeffrey Jargon
13:40 – 14:20	Keynote: The Future of Microwave Measurements in a World of Learning Machines A1 Mark Pierpoint Keysight
14:20 – 14:40	On Downconverter Noise Characterization for LO Waveform Sensitivities A2 Jon Martens Anritsu
14:40 – 15:00	An Adaptable Time Domain Gating Implementation with Enhanced Edge Treatment for Facilitating Vector Frequency Domain Data Analyses A3 Zhong Chen ETS-Lindgren
15:00 – 15:50	Break - Exhibits

Monday, January 22nd

♀ Republic ABC	
15:50 – 17:00	Session B: On-Wafer measurements and Calibration Session Chair: Rusty Myers
15:50 – 16:20	Invited: On-wafer THz Electronic Characterization
B1	Jerome Cheron NIST
16:20 – 16:40	Precision Printed Circuit Board Probing Into W-Band Frequencies
B2	Hugo Morales, Larry Dunleavy, Chris DeMartino Modelithics Inc.
16:40 – 17:00	Error-Box Calibration of Three-Sampler VNAs
B3	Ziad Hatab, Michael E Gadringer, Wolfgang Bösch Graz University of Technology

Tuesday, January 23rd

♀ Republic ABC	
8:20 – 9:30	<p>Session C: Advances in Measurements II</p> <p>Session Chair: Joe Gering</p>
8:20 – 8:50	<p>Invited: Complex Modulation and Signal Recovery in High-Frequency Measurements</p>
C1	Dan van der Weide AntenneX
8:50 – 9:10	Efficient Calibration of RFSoc Full Digital Receiving Beamformer
C2	Peizhuo Yang, Jiahao Wang, Koen Mouthaan National University of Singapore
9:10 – 9:30	Double-pulse Load-Pull for Trapping Characterization of GaN Transistors
C3	Mauro Marchetti, Gustavo Avolio, Nikolai Balovnev Anteverta-mw B.V. Martino Lorenzini Gallium Semiconductor
9:30 – 10:10	Break - Exhibits
♀ Lonestar Ballroom ABC	
10:10 – 12:00	RWW/ARFTG Joint Plenary Session
♀ Presidio ABC	
12:00 – 13:30	ARFTG Awards Lunch

Tuesday, January 23rd

♀ Presidio ABC	
13:30 – 13:50	ARFTG Business Meeting
♀ Republic ABC	
13:50 – 15:00	Session D: On-Wafer and EVM Measurements Session Chair: Joel Dunsmore
13:50 – 14:20	Invited: Optimizing Vector Network Analyzer on-wafer LRRM Calibration Structures for Measurement of GaAs Devices
D1	Leonard Hayden Qorvo
14:20 – 14:40	Discrimination Between Noise and Distortion in EVM Measurements
D2	Jacques B. Sombrin TESA Laboratory Benjamin Ros, Aurélien Chaumet CNES
14:40 – 15:00	Identifying Quasi-Identical Power Amplifiers through EVM and NMSE Measurements of Output Data using Digital Post Distortion
D3	Nicholas A Ellis, Patrick Roblin Ohio State University
15:00 – 15:50	Break - Exhibits

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15:50 – 17:00	Session E: Generalized Network Analysis and Load-Pull Session Chair: Dennis Lewis
15:50 – 16:20	Invited: Remote-port Network Analysis: Challenges in Spatially-large Setups
E1	Jon Martens Anritsu
16:20 – 16:40	Benchmarking a High Electron Mobility Transistor Using an Active Load-Pull System at 120 GHz - 170 GHz
E2	Jing Wang University of Glasgow
16:40 – 17:00	Discussion on System-Level Wideband Active Load-Pull Linearity Measurements: How to Reach Broadband Design Techniques?
E3	Ricardo Figueiredo, Sanket Chaudhary University of Aveiro Marc Vanden Bossche NI Mohadig Rousstia Ampleon Mauro Marchetti Anteverta-mw B.V. Nuno Borges Carvalho Instituto de Telecomunicacoes